



Main features

Symbol	Value	Unit
$I_{T(RMS)}$	25	A
V_{DRM}/V_{RRM}	600 and 800	V
$I_{GT} (Q_1)$	35 to 50	mA

Description

Available either in through-hole or surface-mount packages, the **BTA24, BTB24, BTA26** triac series is suitable for general purpose AC switching. They can be used as an ON/OFF function in applications such as static relays, heating regulation, induction motor starting circuits... or for phase control operation in light dimmers, motor speed controllers, ...

The snubberless versions (BTA/BTB...W and T25 series) are specially recommended for use on inductive loads, thanks to their high commutation performances. By using an internal ceramic pad, the BTA series provides voltage insulated tab (rated at $2500V_{RMS}$) complying with UL standards

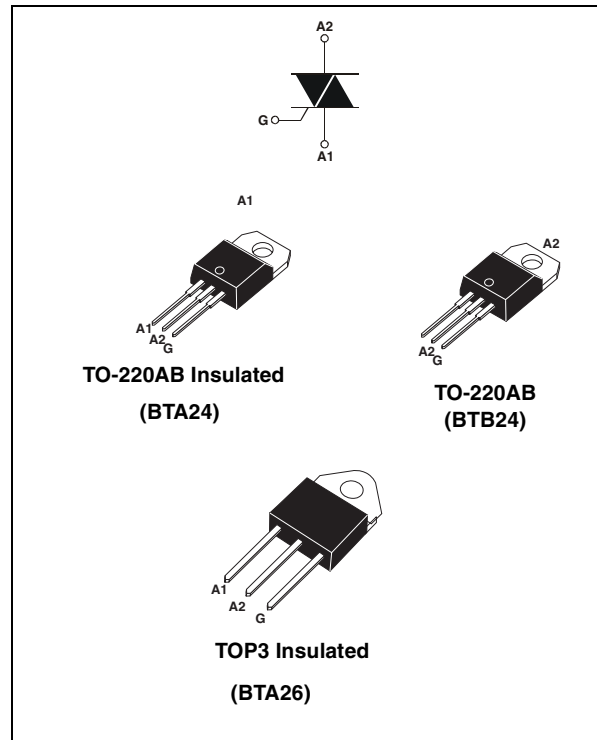


Table 1. Absolute maximum ratings

Symbol	Parameter		Value	Unit	
$I_{T(RMS)}$	RMS on-state current (full sine wave)	D ² PAK / TO-220AB	$T_c = 100^\circ C$	25	A
		RD91 / TOP3 Ins.	$T_c = 90^\circ C$		
		TO-220AB Ins.	$T_c = 75^\circ C$		
I_{TSM}	Non repetitive surge peak on-state current (full cycle, T_j initial = $25^\circ C$)	F = 50 Hz	t = 20 ms	250	A
		F = 60 Hz	t = 16.7 ms	260	
I^2t	I^2t Value for fusing	$t_p = 10$ ms		340	A ² s
di/dt	Critical rate of rise of on-state current $I_G = 2 \times I_{GT}$, $t_r \leq 100$ ns	F = 120 Hz	$T_j = 125^\circ C$	50	A/ μ s
V_{DSM}/V_{RSM}	Non repetitive surge peak off-state voltage	$t_p = 10$ ms	$T_j = 25^\circ C$	$V_{DSM}/V_{RSM} + 100$	V
I_{GM}	Peak gate current	$t_p = 20 \mu$ s		4	A
$P_{G(AV)}$	Average gate power dissipation		$T_j = 125^\circ C$	1	W
T_{stg} T_j	Storage junction temperature range			- 40 to + 150	$^\circ C$
	Operating junction temperature range			- 40 to + 125	

BTA26-BTB26 SCR

Table 2. Electrical characteristics ($T_j = 25^\circ\text{C}$, unless otherwise specified), Snubberless™ and Logic Level (3 quadrants) BTA/BTB24...W, , BTA26...W

Symbol	Test Conditions	Quadrant		T25	BTA/BTB		Unit
				T2535	CW	BW	
$I_{GT}^{(1)}$	$V_D = 12\text{ V}$ $R_L = 33\ \Omega$	I - II - III	MAX.	35	35	50	mA
V_{GT}		I - II - III	MAX.	1.3			V
V_{GD}	$V_D = V_{DRM}$ $R_L = 3.3\ \text{k}\Omega$ $T_j = 125^\circ\text{C}$	I - II - III	MIN.	0.2			V
$I_H^{(2)}$	$I_T = 500\ \text{mA}$		MAX.	50	50	75	mA
I_L	$I_G = 1.2 I_{GT}$	I - III	MAX.	70	70	80	mA
		II		80	80	100	
$dV/dt^{(2)}$	$V_D = 67\% V_{DRM}$ gate open	$T_j = 125^\circ\text{C}$	MIN.	500	500	1000	V/ μs
$(dI/dt)_c^{(2)}$	Without snubber	$T_j = 125^\circ\text{C}$	MIN.	13	13	22	A/ms

1. minimum I_{GT} is guaranteed at 5% of I_{GT} max.

2. for both polarities of A2 referenced to A1.

Table 3. Electrical characteristics ($T_j = 25^\circ\text{C}$, unless otherwise specified), Standard (4 quadrants), BTB24...B, BTA26...B

Symbol	Test Conditions	Quadrant		Value	Unit
$I_{GT}^{(1)}$	$V_D = 12\text{ V}$ $R_L = 33\ \Omega$	I - II - III - IV	MAX.	50 100	mA
V_{GT}		ALL	MAX.	1.3	V
V_{GD}	$V_D = V_{DRM}$ $R_L = 3.3\ \text{k}\Omega$ $T_j = 125^\circ\text{C}$	ALL	MIN.	0.2	V
$I_H^{(2)}$	$I_T = 500\ \text{mA}$		MAX.	80	mA
I_L	$I_G = 1.2 I_{GT}$	I - III - IV	MAX.	70	mA
		II		160	
$dV/dt^{(2)}$	$V_D = 67\% V_{DRM}$ gate open	$T_j = 125^\circ\text{C}$	MIN.	500	V/ μs
$(dV/dt)_c^{(2)}$	$(dI/dt)_c = 13.3\ \text{A/ms}$	$T_j = 125^\circ\text{C}$	MIN.	10	V/ μs

1. minimum I_{GT} is guaranteed at 5% of I_{GT} max.

Table 4. Static characteristics

Symbol	Test Conditions			Value	Unit
$V_T^{(1)}$	$I_{TM} = 35\ \text{A}$ $t_p = 380\ \mu\text{s}$	$T_j = 25^\circ\text{C}$	MAX.	1.55	V
$V_{i0}^{(1)}$	Threshold voltage	$T_j = 125^\circ\text{C}$	MAX.	0.85	V
$R_d^{(1)}$	Dynamic resistance	$T_j = 125^\circ\text{C}$	MAX.	16	m Ω
I_{DRM} I_{RRM}	$V_{DRM} = V_{RRM}$	$T_j = 25^\circ\text{C}$	MAX.	5	μA
		$T_j = 125^\circ\text{C}$		3	mA

1. for both polarities of A2 referenced to A1.

Table 5. Thermal resistance

Symbol	Parameter		Value	Unit	
$R_{th(j-c)}$	Junction to case (AC)		D ² PAK / TO-220AB	0.8	° C/W
			RD91 (Insulated) / TOP3 Insulated	1.1	
			TO-220AB Insulated	1.7	
$R_{th(j-a)}$	Junction to ambient	(¹)S = 1 cm ²	D ² PAK	45	° C/W
			TOP3 Insulated	50	
			TO-220AB / TO-220AB Insulated	60	

1. S = Copper surface under tab.

Figure 1. Maximum power dissipation versus RMS on-state current (full cycle)

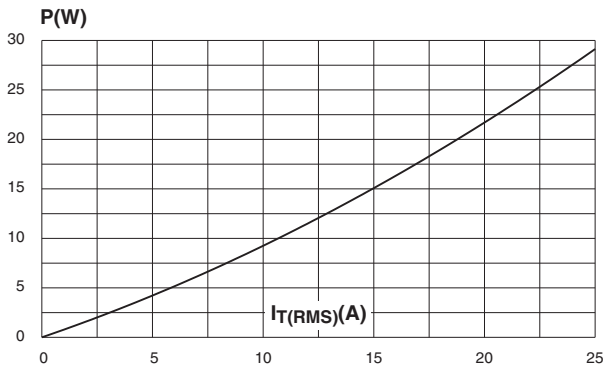


Figure 2. RMS on-state current versus case temperature (full cycle)

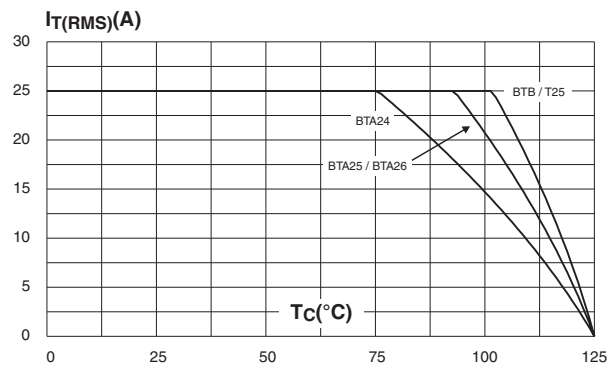


Figure 3. D²PAK RMS on-state current versus ambient temperature (printed circuit board FR4, copper thickness: 35µm) (full cycle)

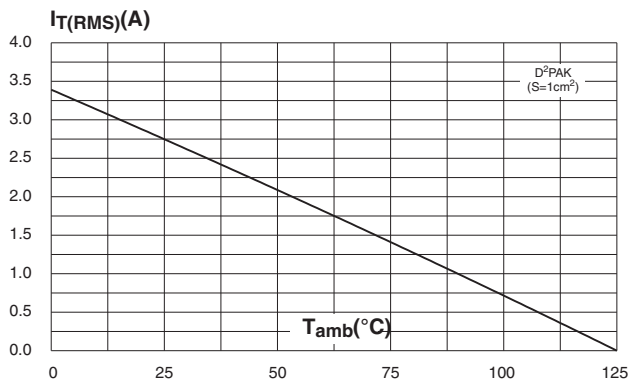


Figure 4. Relative variation of thermal impedance versus pulse duration

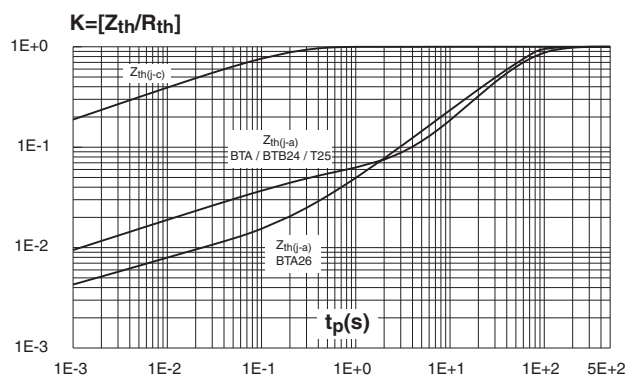


Figure 5. On-state characteristics (maximum values)

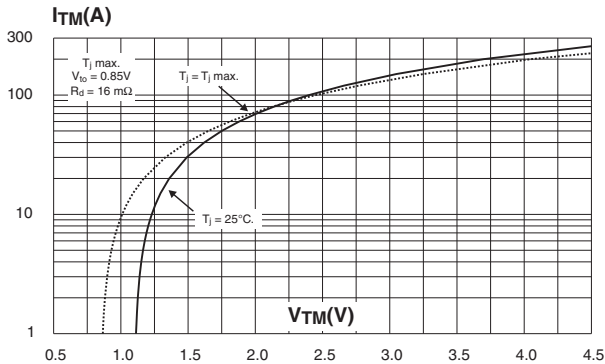


Figure 6. Surge peak on-state current versus number of cycles

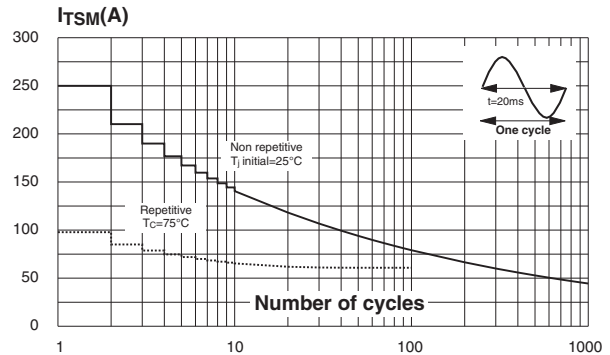


Figure 7. Non-repetitive surge peak on-state current for a sinusoidal pulse with width $t_p < 10$ ms and corresponding value of I^2t

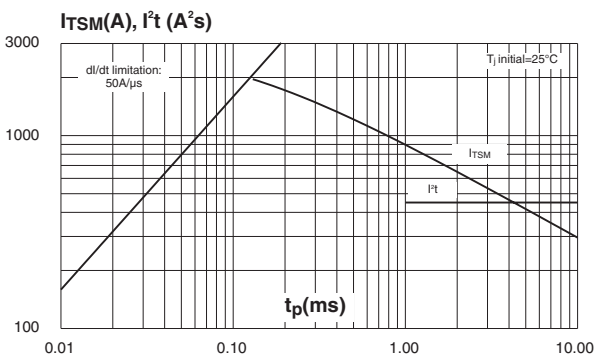


Figure 8. Relative variation of gate trigger current, holding current and latching current versus junction temperature (typical values)

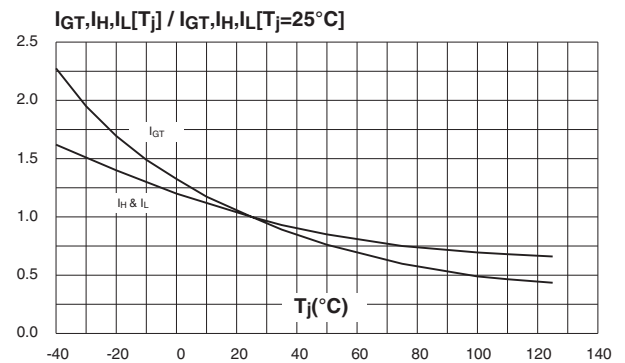


Figure 9. Relative variation of critical rate of decrease of main current versus $(dV/dt)_c$ (typical values)

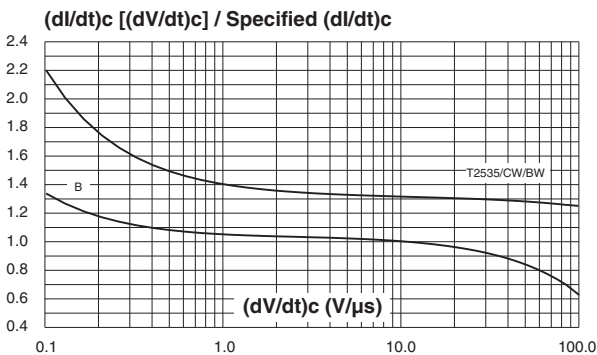


Figure 10. Relative variation of critical rate of decrease of main current versus $(dV/dt)_c$

